

<b>INFORMATION DISCLOSURE CITATION IN AN APPLICATION</b>  (PTO-1449)				ATTY. DOCKET NO. <b>57454-981</b>		SERIAL NO. (Continuation of Serial No. <del>40/062,462</del> )			
				APPLICANT <b>Yasuo INOUE, et al.</b>				<i>10/743771</i>	
				FILING DATE <b>December 24, 2003</b>		GROUP <b>Not yet assigned</b>			
<b>U.S. PATENT DOCUMENTS</b>									
EXAMINER'S INITIALS	PATENT NO.	DATE	NAME	CLASS	SUBCLASS	FILING DATE			
<i>MEW</i>	4,478,655	10/23/84	Nagakubo et al.	1	7				
	5,440,161	8/8/95	Iwamatsu et al.						
	4,696,092	9/29/87	Doering et al.						
	5,164,326	11/17/92	Foerstner et al.						
	5,856,695	1/5/99	Ito et al.						
	4,996,575	2/26/91	Ipri et al.						
	5,652,454	07/97	Iwamatsu et al.						
<b>FOREIGN PATENT DOCUMENTS</b>									
EXAMINER'S INITIALS	FOREIGN PATENT DOCUMENT Country Codes-Number + Kind Codes (if known)	PUBLICATION DATE	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines Where Relevant Figures Appear	Translation				
					Yes	No			
<i>MEW</i>	JP 5-182909	7/93	1	7					
	JP 53-68990	6/78							
	JP 62-104136	5/87							
	JP 03-187241	8/91							
	JP 61-034978	02/86							
<b>OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)</b>									
<i>MEW</i>	"A High Speed and Lower Power Consumption 16 K Gate Array on Ultra Thin SOI Film", by Y. Yamaguchi et al., Institute of Information and Communication Engineers of Japan, pp. 81-86, 1992.								
EXAMINER <i>Makoto M</i>				DATE CONSIDERED <i>1/20/04</i>					

EXAMINER: Initial if reference considered, whether or not citation is in conformance MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.

# INFORMATION DISCLOSURE CITATION IN AN APPLICATION

(PTO-1449)

ATTY. DOCKET NO.  
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YASUO INOUE, et al.

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## U.S. PATENT DOCUMENTS

EXAMINER'S INITIALS	CITE NO.	Document Number Number-Kind Code <sup>2</sup> (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		US			
		US			
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## FOREIGN PATENT DOCUMENTS

EXAMINER'S INITIALS	CITE NO.	Foreign Patent Document Country Code <sup>2</sup> -Number + Kind Codes (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines Where Relevant Figures Appear	Translation	
						Yes	No
NEW		JP 04-014275	1/92	Omron Corp		Partial	
		JP 04-034980	2/92	Mitsubishi Electric Corp		Partial	
		JP 04-199574	7/92	Mitsubishi Electric Corp		Partial	

## OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)

EXAMINER'S INITIALS	CITE NO.	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.

EXAMINER

Matthew E. Wane

DATE CONSIDERED

1/20/04

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1 Applicant's unique citation designation number (optional). 2 Applicant is to place a check mark here if English language Translation is attached.